

# Semiconductor Devices Review

Fermi-dirac distribution :  $f(E) = \frac{1}{1 + e^{(E-E_F)/kT}}$

↳ Boltzmann Approximation :  $E - E_F \gg kT \Rightarrow f(E) \approx e^{-(E-E_F)/kT}$

Electron concentration :  $n = \int_{E_c}^{\text{Top of conduction band } \approx \infty} f(E) \rho_c(E) dE$  where  $\rho_c(E) \equiv$  Density of states in conduction band

↳ For  $E - E_F \gg kT$  :  $n \approx N_c e^{-(E_c - E_F)/kT}$  where  $N_c = 2 \left[ \frac{2\pi m_n kT}{h^2} \right]^{3/2}$

↳ For holes :  $p \approx N_v e^{-(E_F - E_v)/kT}$  where  $N_v = 2 \left[ \frac{2\pi m_p kT}{h^2} \right]^{3/2}$

↳ For Si at 300K :  $N_c \approx 2.8 \times 10^{19} \text{ cm}^{-3}$  and  $N_v \approx 1.04 \times 10^{19} \text{ cm}^{-3}$

PN Product :  $np = n_i^2$  where  $n_i = \sqrt{N_c N_v} e^{-E_g/kT}$  ↳ Intrinsic carrier concentration

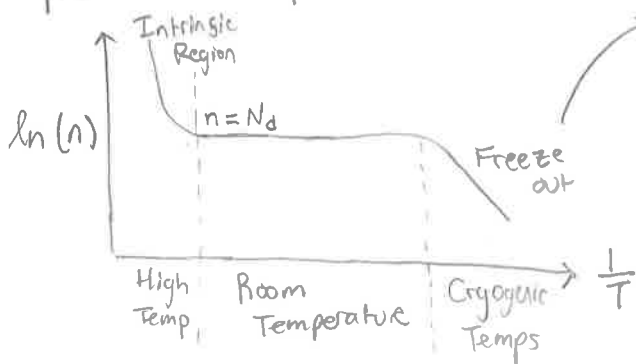
↳ Intrinsic Semiconductor : No dopants  $\rightarrow n = p = n_i$

⚠ Charge Neutrality requires that  $n + N_a = p + N_d$  ↳ Acceptor ion concentration ↳ Donor ion concentration

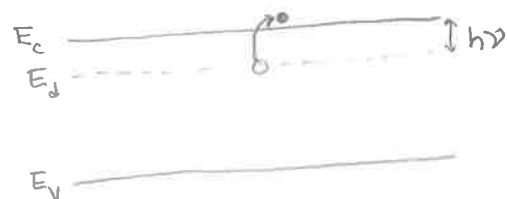
↳  $N_d - N_a \gg n_i \Rightarrow n \approx N_d - N_a ; p \approx n_i^2/n$

↳  $N_a - N_d \gg n_i \Rightarrow p \approx N_a - N_d ; n \approx n_i^2/p$

Temperature dependence of electron concentration :



can use Freeze out For IR detector :



Operate semiconductor in Freezeout so none of donor ions are ionized. Incident photons excite electron from donor level to conduction band



## Scattering Mechanisms:

(1) Phonon Scattering: electrons scatter off of phonon "particles"

$$\rightarrow \mu_{\text{phonon}} = \frac{q \tau_{\text{ph}}}{m} \propto T^{-3/2}$$

(2) Impurity Ion Scattering: repulsive or attractive forces between electrons and impurity/dopant ions deflects electrons.

$$\rightarrow \mu_{\text{impurity}} \propto \frac{T^{3/2}}{N_a + N_d}$$

(3) Total scattering rate/Mobility:  $\frac{1}{\tau} = \frac{1}{\tau_{\text{phonon}}} + \frac{1}{\tau_{\text{impurity}}}$ ;  $\frac{1}{\mu} = \frac{1}{\mu_{\text{phonon}}} + \frac{1}{\mu_{\text{impurity}}}$

Velocity Saturation: In small devices, electric fields can be large which excite electrons to high velocities  $\rightarrow$  If electron energy exceeds optical phonon energy, electrons will release energy as optical phonon  $\rightarrow$  leads to maximum energy and hence saturated velocity

$$\rightarrow v_{\text{sat}} = \sqrt{\frac{2E_{\text{opt}}}{m}} \sim 10^7 \text{ cm/s}$$

## Drift Current & Conductivity:

$$\rightarrow \text{Drift current: } J_{p,\text{drift}} = q p v_{\text{drift},p} = q p \mu_p E$$

$$J_{n,\text{drift}} = -q n v_{n,\text{drift}} = q n \mu_n E$$

$$\Rightarrow J_{\text{tot}} = J_{p,\text{drift}} + J_{n,\text{drift}} = (q p \mu_p + q n \mu_n) E = J_{\text{tot}}$$

$$\rightarrow \text{Conductivity: } J = \sigma E \Rightarrow \sigma = q p \mu_p + q n \mu_n$$

Negative to match correct direction that charge flows

$$\text{Diffusion Current: } J_{n,\text{diff}} = q D_n \frac{dn}{dx} ; J_{p,\text{diff}} = -q D_p \frac{dp}{dx}$$

$$\text{Total Current: } J_n = J_{n,\text{drift}} + J_{n,\text{diff}} = q n \mu_n E + q D_n \frac{dn}{dx}$$

$$J_p = J_{p,\text{drift}} + J_{p,\text{diff}} = q p \mu_p E - q D_p \frac{dp}{dx}$$

$$\Rightarrow J = J_n + J_p = \sigma E + q D_n \frac{dn}{dx} - q D_p \frac{dp}{dx}$$

Einstein Relationship:  $D_n = \frac{kT}{q} \mu_n$ ;  $D_p = \frac{kT}{q} \mu_p$

Electron-Hole Generation and Recombination:

↳ Excess carrier concentration:  $\begin{cases} n \equiv n_0 + n' \\ p \equiv p_0 + p' \end{cases}$   $n_0 \equiv$  equilibrium carrier concentration

↳ Charge neutrality:  $n' = p'$

↳ Recombination  $\rightarrow n'$  &  $p'$  will naturally return to 0

$\frac{dn'}{dt} = -\frac{n'}{\tau} = -\frac{p'}{\tau} \Rightarrow \frac{n'}{\tau} = \frac{p'}{\tau} \equiv$  Recombination Rate

This seems weird...  $\left\{ \begin{array}{l} np = n_i^2 \Rightarrow \text{Generation} = \text{Recombination}; \quad np > n_i^2 \Rightarrow \text{net Recombination} \\ np < n_i^2 \Rightarrow \text{Net Generation} \end{array} \right.$

Quasi-Equilibrium:  $np \neq n_i^2 \Rightarrow$  Semiconductor NOT in equilibrium

↳ Quasi-fermi levels:  $n = N_c e^{-(E_c - E_{fn})/kT}$

$p = N_v e^{-(E_{fp} - E_v)/kT}$

$\Rightarrow np = N_c N_v e^{-(E_g - E_{fn} + E_{fp})/kT} = n_i^2 e^{(E_{fn} - E_{fp})/kT} = \boxed{n_i^2 e^{\Delta\phi/kT}}$

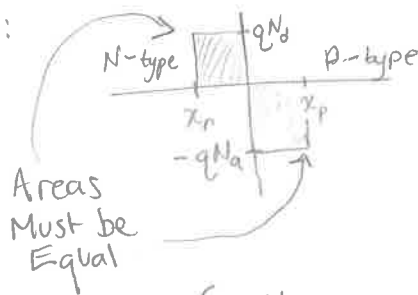
# PN Junctions

depletion layer:  $n \approx 0$ ;  $p \approx 0$

Built in Potential:  $\phi_{bi} = B - A = \frac{kT}{q} \ln \frac{N_d N_a}{n_i^2}$

Poisson's Equation:  $\frac{d^2 V}{dx^2} = -\frac{\rho}{\epsilon_s}$  ( $\leftarrow \nabla \cdot \vec{D} = \rho$ )

Charge distribution:



Electric field continuity Requires:

$$N_a |x_p| = N_d |x_n|$$

Electric Potential: 
$$V(x) = \begin{cases} -\frac{qN_a}{2\epsilon_s} (x_p - x)^2 & (0 \leq x \leq x_p) \\ \phi_{bi} - \frac{qN_d}{2\epsilon_s} (x - x_n)^2 & (-x_n \leq x \leq 0) \end{cases}$$

Depletion Layer Width:  $W_{dep} = x_p - x_n = \sqrt{\frac{2\epsilon_s \phi_{bi}}{q} \left( \frac{1}{N_a} + \frac{1}{N_d} \right)}$   $\rightarrow$  Largely determined by lighter dopant

$\hookrightarrow$  Under bias:  $W_{dep} = \sqrt{\frac{2\epsilon_s (\phi_{bi} - V)}{qN}}$  where  $\frac{1}{N} = \frac{1}{N_a} + \frac{1}{N_d}$ ;  $V > 0$  for FWD bias,  $V < 0$  for Rev bias

Depletion Layer capacitance:  $C_{dep} = A \frac{\epsilon_s}{W_{dep}}$

$\hookrightarrow \Rightarrow \frac{1}{C_{dep}^2} = \frac{2(\phi_{bi} + V_r)}{qN\epsilon_s A^2} \rightarrow \begin{cases} \text{Slope gives } N \\ \text{x-intercept gives } \phi_{bi} \end{cases}$

## Breakdown under reverse bias:

$\hookrightarrow$  As reverse bias increased, electric field across junction increases until breakdown occurs  $\rightarrow V_B = \frac{\epsilon_s E_{crit}}{2qN} - \phi_{bi}$

$\hookrightarrow$  Tunneling breakdown: goes as  $\sim \exp(-H/E)$  where  $H \sim E_g^{3/2} m^*{}^{1/2}$ , critical field is  $\sim 10^6$  V/cm, occurs when  $N$  is very high and  $V_B$  is quite low

↳ Avalanche breakdown: high energy electrons in conduction band traveling through depletion layer can excite new electrons up from valence band. The corresponding hole in the valence band can excite a new electron-hole pair as it accelerates through the depletion layer starting the process all over again

Forward Bias: Carrier Injection: under forward bias, the potential barrier at the junction is reduced, allowing electrons on the n-side and holes on the p-side to diffuse across the junction → current flows

↳ Minority Carrier density

$$\begin{cases} n(x_p) = n_{p0} e^{qV/kT} = \frac{n_i^2}{N_a} e^{qV/kT} \\ p(x_n) = p_{n0} e^{qV/kT} = \frac{n_i^2}{N_d} e^{qV/kT} \end{cases}$$

△ Minority carrier densities are elevated by factor  $e^{qV/kT}$

↳ Excess minority carrier density:

$$\begin{cases} n'(x_p) = n_{p0} (e^{qV/kT} - 1) = n(x_p) - n_{p0} \\ p'(x_n) = p_{n0} (e^{qV/kT} - 1) = p(x_n) - p_{n0} \end{cases}$$

↳ Current Continuity Equations:

$$\begin{cases} \frac{d^2 p'}{dx^2} = \frac{p'}{L_p^2} & \text{where } L_p = \sqrt{D_p \tau_p} \equiv \text{diffusion length for holes} \\ \frac{d^2 n'}{dx^2} = \frac{n'}{L_n^2} & \text{where } L_n = \sqrt{D_n \tau_n} \equiv \text{diffusion length for } e^- \end{cases}$$

Solved using B.C.:  $p'(\infty) = 0$ ;  $p'(x_n) = p_{n0} (e^{qV/kT} - 1)$

PN Diode IV Characteristics: Injected Minority carriers diffuse away from junction ⇒ Net current

↳ Recall:  $J_{p, drift} = -q D_p \frac{dp'(x)}{dx} \rightarrow J_{tot, drift} = q D_n \frac{dn'(x)}{dx} - q D_p \frac{dp'(x)}{dx}$

↳ Plugging in:  $J_{tot, drift} = \left( q \frac{D_p}{L_p} p_{n0} + q \frac{D_n}{L_n} n_{p0} \right) (e^{qV/kT} - 1)$

Since  $I = \int d\vec{a} \cdot \vec{J} \approx AJ \Rightarrow$

$$I = I_0 (e^{qV/kT} - 1)$$

where  $I_0 = Aq n_i^2 \left( \frac{D_p}{L_p N_d} + \frac{D_n}{L_n N_a} \right)$

$\rightarrow I_0 \equiv$  Reverse Saturation Current  $\rightarrow$  As  $V \rightarrow -\infty$ ,  $I \rightarrow -I_0$   
ie current saturates to  $I_0$  under reverse bias

Charge storage: Under Forward bias, diodes store charge which is proportional to  $p'_N(0)$  and  $n'_P(0)$ .

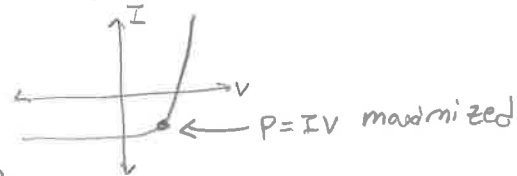
$$\Rightarrow Q \propto I \Rightarrow I = Q/\tau_s \text{ where } \tau_s \equiv \text{charge storage time.}$$

$\rightarrow$  This gives rise to diffusion capacitance.

$$C = \frac{dQ}{dV} = \frac{d}{dV}(I\tau_s) = \tau_s \frac{dI}{dV} = \tau_s \frac{I_{DC}}{kT/q} = C_{diff}$$

Solar Cells: Photons absorbed w/in a diffusion length of the junction can generate minority carriers which are swept across the junction by the built-in potential  $\rightarrow$  short circuit current

$$I = I_0 (e^{qV/kT} - 1) - I_{sc}$$



$\rightarrow$  External load must be matched to cell such that it operates at it's optimum.

⚠  $\frac{hc}{\lambda} \sim \frac{1.24}{\lambda} (\mu m)$

$\rightarrow$  Short circuit current & Open Circuit Voltage:

Minority carrier concentration modified:  $\frac{d^2 p'}{dx^2} = \frac{p'}{L_p^2} - \frac{G}{D_p}$

with boundary conditions:  $p'(0) = 0$ ,  $p'(\infty) = \text{const} \Rightarrow \frac{d^2 p'}{dx^2} = 0$ .

$$\Rightarrow p'(\infty) = L_p^2 \frac{G}{D_p} = \tau_p G$$

$\swarrow$  rate of generation due to incident light

Solving the DEQ:  $p'(x) = \tau_p G (1 - e^{-x/L_p})$

$$\text{So, } J_p = -q D_p \frac{dp'}{dx} = q \frac{D_p}{L_p} \tau_p G e^{-x/L_p}$$

$$\text{And } I_{sc} = A J_p(0) = \boxed{A q L_p G = I_{sc}}$$



# Quantum Review

Schrodinger's Equation is:

$$\hat{H} \Psi(\vec{r}, t) = i\hbar \frac{\partial}{\partial t} \Psi(\vec{r}, t)$$

Where the Hamiltonian operator is given by:

$$\begin{aligned} \hat{H} &= \frac{p^2}{2m} + V(\vec{r}, t) = + \frac{(i\hbar \nabla)^2}{2m} + V(\vec{r}, t) \\ &= -\frac{\hbar^2 \nabla^2}{2m} + V(\vec{r}, t) \end{aligned}$$

Thus:

$$\left[ -\frac{\hbar^2 \nabla^2}{2m} + V(\vec{r}, t) \right] \Psi(\vec{r}, t) = i\hbar \frac{\partial}{\partial t} \Psi(\vec{r}, t)$$

For simplicity, assume that  $\Psi(\vec{r}, t)$  has time harmonic dependence,

ie  $\Psi(\vec{r}, t) = \Psi(\vec{r}) e^{-i\omega t}$  and  $V(\vec{r}, t) = V(\vec{r}) e^{-i\omega t}$

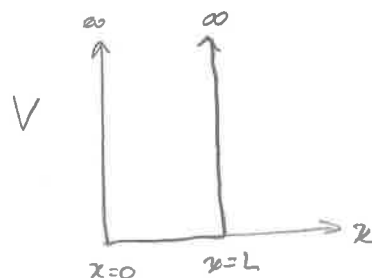
Schrodinger's Equation thus simplifies to the time-independent form:

$$\left[ \frac{-\hbar^2 \nabla^2}{2m} + V(\vec{r}) \right] \Psi(\vec{r}) = E \Psi(\vec{r}) \quad \text{where } \underline{E = \hbar\omega}$$

To solve this equation we must specify a potential  $V(\vec{r})$ .

Let us first consider an infinite square well:

$$V(\vec{r}) = \begin{cases} 0 & 0 < x < L \\ \infty & \text{else} \end{cases}$$



For this set of boundary conditions, we must find  $\psi(x)$  for the case that  $V=0$  and enforce boundary conditions such that  $V \rightarrow \infty$  outside the well:

$$-\frac{\hbar^2}{2m} \frac{\partial^2 \psi(x)}{\partial x^2} = E \psi(x) \Rightarrow \frac{\hbar^2}{2m} \frac{\partial^2 \psi}{\partial x^2} + E \psi = 0$$

Consider the trial solution,  $\psi(x) = e^{ax}$ :

$$\Rightarrow \frac{\hbar^2}{2m} a^2 + E = 0 \Rightarrow a^2 = -\frac{2mE}{\hbar^2} \Rightarrow a = \pm i \sqrt{\frac{2mE}{\hbar^2}} = \pm ik$$

Thus

$$\psi(x) = A e^{ikx} + B e^{-ikx} \quad \text{where} \quad k = \sqrt{\frac{2mE}{\hbar^2}}$$

Alternatively, we can write:

$$\psi(x) = A \sin(kx) + B \cos(kx)$$

Since  $V \rightarrow \infty$  at the boundary of, we require that

$$\psi(x=0) = \psi(x=L) = 0;$$

$\psi(x=0) = 0$  gives  $B=0$  while  $\psi(x=L) = 0$  gives

$$A \sin(kL) = 0 \Rightarrow kL = \pi n \Rightarrow k = \frac{\pi n}{L} \quad \text{for } n \in \mathbb{I}$$

There is a final condition we must apply:  $|\psi(x)|^2$  gives the probability of measuring an electron at a location  $x$ . The wavefunction must thus be properly normalized:

$$\int_0^L dx |\psi(x)|^2 = 1 \Rightarrow \int_0^L dx A^2 \sin^2(kx) = 1$$

$$\Rightarrow A^2 \left[ \frac{x}{2} - \frac{\sin(2kx)}{4k} \right]_0^L = A^2 \left[ \frac{L}{2} - \frac{\sin(2\frac{\pi n}{L}L)}{4k} \right] = A^2 \frac{L}{2} = 1$$

$$\Rightarrow \underline{\underline{A = \sqrt{\frac{2}{L}}}}$$

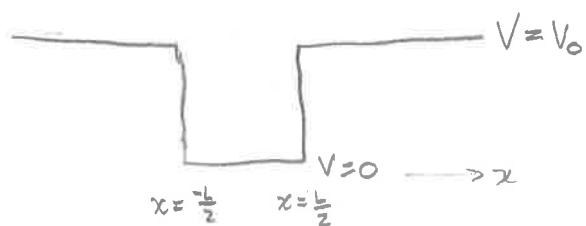
Thus the wavefunction which satisfies the infinite square well potential is:

$$\psi(x) = \sqrt{\frac{2}{L}} \sin\left(\frac{n\pi x}{L}\right)$$

Furthermore, this implies that the electron energy is quantized since,

$$k = \frac{n\pi}{L} = \sqrt{\frac{2m^*E}{\hbar^2}} \Rightarrow E = \frac{\hbar^2 \pi^2}{2m^*} \left(\frac{n}{L}\right)^2 \text{ for } n \in \mathbb{N}$$

Next, consider a non-infinite square-well:



$$V(x) = \begin{cases} 0 & |x| < \frac{L}{2} \\ V_0 & |x| > \frac{L}{2} \end{cases}$$

Here we must solve three forms of SE:

